

**Notice of References Cited**

Application/Control No.

10/552,439

Applicant(s)/Patent Under  
Reexamination  
ASADA ET AL.

Examiner

CHIA-WEI A. CHEN

Art Unit

2622

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*	B	US-2004/0033051	02-2004	IP, Kiril Kun Wan	386/35
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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